

<b>Notice of References Cited</b>	Application/Control No. 10/706,917		Applicant(s)/Patent Under Reexamination GU ET AL.	
	Examiner Barry J. Gooden Jr.		Art Unit 3616	Page 1 of 3

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,240,283 A	08-1993	Kishi et al.	280/729
*	B	US-2001/0026062 A1	10-2001	Kosugi et al.	280/730.2
*	C	US-2001/0042974 A1	11-2001	SASAKI et al.	280/728.2
*	D	US-6,471,244 B1	10-2002	Nishijima et al.	280/742
*	E	US-5,464,250	11-1995	Sato, Koki	280/743.1
*	F	US-6,450,529	09-2002	Kalandek et al.	280/730.2
*	G	US-2003/0178831 A1	09-2003	Roberts et al.	280/743.1
*	H	US-2004/0119269 A1	06-2004	Yokota et al.	280/730.2
*	I	US-6,398,253	06-2002	Heigl, Jorgen	280/730.2
*	J	US-6,364,350	04-2002	Hoagland, Larry D.	280/730.2
*	K	US-6,364,348	04-2002	Jang et al.	280/730.2
*	L	US-6,962,363 B2	11-2005	Wang et al.	280/729
*	M	US-6,279,944	08-2001	Wipasuramonton et al.	280/730.2

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
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	S					
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#### NON-PATENT DOCUMENTS

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<b>Notice of References Cited</b>	Application/Control No. 10/706,917		Applicant(s)/Patent Under Reexamination GU ET AL.	
	Examiner Barry J. Gooden Jr.		Art Unit 3616	Page 2 of 3

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,059,311	05-2000	Wipasuramonton et al.	280/729
*	B	US-6,065,772	05-2000	Yamamoto et al.	280/730.2
*	C	US-5,853,191	12-1998	Lachat, Michael J.	280/730.2
*	D	US-5,791,685	08-1998	Lachat et al.	280/743.1
*	E	US-2001/0033072	10-2001	Kumagai et al.	280/730.1
*	F	US-2004/0145162	07-2004	Abe et al.	280/729
*	G	US-2003/0107205	06-2003	Gu, Weixin	280/729
*	H	US-2003/0034637	02-2003	Wang et al.	280/729
*	I	US-6,464,249	10-2002	Lacroix, Donald R.	280/729
*	J	US-6,419,267	07-2002	Hashimoto et al.	280/743.1
*	K	US-619,267	02-1899	Name not available	493/75
*	L	US-6,059,312	05-2000	Staub et al.	280/729
*	M	US-5,529,337	06-1996	Takeda et al.	280/729

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
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	Examiner Barry J. Gooden Jr.		Art Unit 3616	Page 3 of 3

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,086,092	07-2000	Hill, Bruce	280/729
*	B	US-4,043,572	08-1977	Hattori et al.	280/738
*	C	US-5,713,598	02-1998	Morita et al.	280/743.1
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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